



## ABSOLUTE MAXIMUM RATINGS (Beyond which damage may occur)<sup>1</sup> 25 °C

### Supply Voltages

AV <sub>DD</sub> .....	-0.3 V to +6.5 V
DV <sub>DD</sub> .....	-0.3 V to +6.5 V
AGND, DGND, RGND .....	-0.3 V to +0.3 V
AGND – DGND .....	±300 mV

### Input Voltages

Digital Inputs .....	-0.3 V to DV <sub>DD</sub> + 0.3 V
V <sub>REF</sub> , R <sub>SET</sub> .....	-0.3 V to AV <sub>DD</sub> + 0.3 V
COMP .....	-0.3 V to AV <sub>DD</sub> + 0.3 V

### Output

I <sub>OUTA</sub> , I <sub>OUTB</sub> Current .....	15 mA
I <sub>OUTA</sub> , I <sub>OUTB</sub> Voltage .....	-1.0 to AV <sub>DD</sub> + 0.3 V

### Temperature

Operating Temperature .....	-40 to +85 °C
Junction Temperature .....	+175 °C
Lead Temperature, (soldering 10 seconds) .....	+300 °C
Storage Temperature .....	-65 to +150 °C

Note 1: Operation at any Absolute Maximum Rating is not implied. See Electrical Specifications for proper nominal applied conditions in typical applications.

## ELECTRICAL SPECIFICATIONS

T<sub>A</sub>=T<sub>MIN</sub> to T<sub>MAX</sub>, AV<sub>DD</sub>=DV<sub>DD</sub>=+5.0 V, unless otherwise specified.

PARAMETERS	TEST CONDITIONS	TEST LEVEL	MIN	SPT5320 TYP	MAX	UNITS
<b>DC Performance</b>						
Resolution				12		Bits
Differential Linearity	25 °C			±0.5		LSB
Differential Linearity	Full Temp.			±1.0		LSB
Integral Linearity	25 °C			±1.0		LSB
Integral Linearity	Full Temp.			±2.0		LSB
Offset Error					±0.025	% FS
Gain Error (without internal reference)				±2	±10	% FS
Gain Error (with internal reference)				±1	±10	% FS
Full-Scale Output Current				20.48		mA
Output Compliance Voltage			-1.0		+1.25	V
Equivalent Output Resistance				>100		kΩ
Gain Error Tempco				tbd		PPM/°C
Zero-Scale Offset Error					±0.025	% FS
Output Capacitance				5		pF
Offset Drift				tbd		ppm FS/°C
Gain Drift (without internal reference)				±50		ppm FS/°C
Gain Drift (with internal reference)				±100		ppm FS/°C
<b>Dynamic Performance</b>						
Maximum Output Update Rate				160		MWPS
Output Settling Time (to 0.1%)				25	35	ns
Output Propagation Delay				tbd		ns
Glitch Impulse				5		pV-s
Output Rise Time (10% to 90%)				tbd		ns
Output Fall Time (10% to 90%)				tbd		ns
Output Noise (I <sub>OUTFS</sub> = 10 mA)				25	50	pA/√Hz
Spurious Free Dynamic Range to Nyquist						
f <sub>CLK</sub> = 50 MHz; f <sub>OUT</sub> = 20 MHz				67		dBc
f <sub>CLK</sub> = 100 MHz; f <sub>OUT</sub> = 20 MHz				67		dBc
f <sub>CLK</sub> = 160 MHz; f <sub>OUT</sub> = 20 MHz				63		dBc
Spurious Free Dynamic Range within a Window						
f <sub>CLK</sub> = 50 MHz; f <sub>OUT</sub> = 5 MHz; 2 MHz Span				86		dBc
f <sub>CLK</sub> = 100 MHz; f <sub>OUT</sub> = 5 MHz; 4 MHz Span				86		dBc
Multitone Power Ratio (8 Tones at 110 kHz Spacing)						
f <sub>CLK</sub> = 20 MHz; f <sub>OUT</sub> = 2.00 to 2.99 MHz				75		dBc

# ELECTRICAL SPECIFICATIONS

$T_A = T_{MIN}$  to  $T_{MAX}$ ,  $AV_{DD} = DV_{DD} = +5.0$  V, unless otherwise specified.

PARAMETERS	TEST CONDITIONS	TEST LEVEL	MIN	SPT5320 TYP	MAX	UNITS
<b>Power Supply Requirements</b>						
Analog Supply Voltage $AV_{DD}$			4.5		5.5	V
Digital Supply Voltage $DV_{DD}$			2.7		5.5	V
Analog Supply Current				tbd	tbd	mA
Digital Supply Current				tbd	tbd	mA
Supply Current Sleep Mode				tbd	5	mA
Power Dissipation						
At +3 V Supplies and 10 mA Current Output				100		mW
At +5 V Supplies and 10 mA Current Output				300		mW
Power Supply Rejection Ratio ( $AV_{DD}$ )				$\pm 0.02$	$\pm 0.2$	%FS/V
Power Supply Rejection Ratio ( $DV_{DD}$ )				$\pm 0.002$	$\pm 0.025$	%FS/V
<b>Reference</b>						
Reference Voltage				1.20		V
Reference Output Current				tbd		
Reference Input Compliance Range			0.1		1.25	V
Small Signal Bandwidth				tbd		MHz
Reference Voltage Drift				$\pm 50$		ppm/ $^{\circ}$ C
<b>Digital Inputs</b>						
Logic "1" Voltage ( $DV_{DD} = +3$ V)			2.1			V
Logic "0" Voltage ( $DV_{DD} = +3$ V)					0.9	V
Logic "1" Voltage ( $DV_{DD} = +5$ V)			3.5			V
Logic "0" Voltage ( $DV_{DD} = +5$ V)					1.3	V
Logic "1" Current			-10		+10	$\mu$ A
Logic "0" Current			-10		+10	$\mu$ A
Input Capacitance				3	5	pF
Input Setup Time – $t_S$			2	<1		ns
Input Hold Time – $t_H$			2	<1		ns
Latch Pulse Width – $t_{LPW}$			tbd			ns

## TEST LEVEL CODES

All electrical characteristics are subject to the following conditions:

All parameters having min/max specifications are guaranteed. The Test Level column indicates the specific device testing actually performed during production and Quality Assurance inspection. Any blank section in the data column indicates that the specification is not tested at the specified condition.

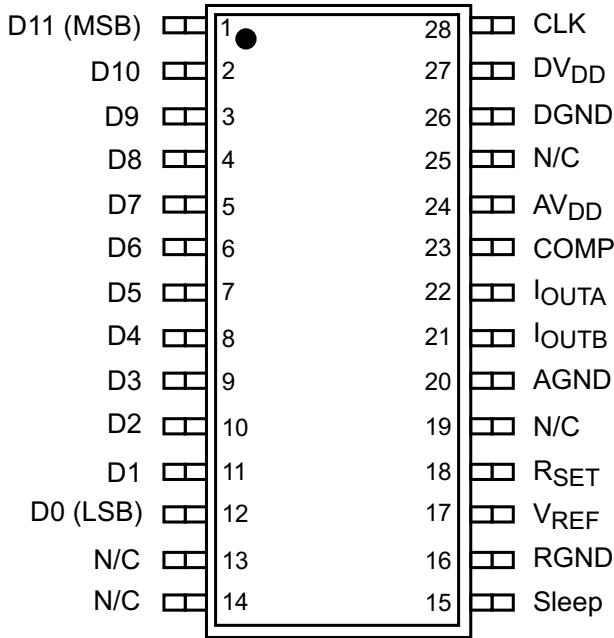
## TEST LEVEL

- I
- II
- III
- IV
- V
- VI

## TEST PROCEDURE

- 100% production tested at the specified temperature.
- 100% production tested at  $T_A = +25$   $^{\circ}$ C, and sample tested at the specified temperatures.
- QA sample tested only at the specified temperatures.
- Parameter is guaranteed (but not tested) by design and characterization data.
- Parameter is a typical value for information purposes only.
- 100% production tested at  $T_A = +25$   $^{\circ}$ C. Parameter is guaranteed over specified temperature range.

## PIN ASSIGNMENTS



## PIN FUNCTIONS

Name	Function
<b>ANALOG OUTPUTS</b>	
IOUTA	DAC current output.
IOUTB	Complementary current output.
<b>DIGITAL INPUTS</b>	
D0–D11	Digital Inputs (D0 is the LSB)
Sleep	Sleep mode pin. Active high. Contains active pull-down resistor.
CLK	Clock input pin. Data is latched on the rising edge.
<b>REFERENCE &amp; COMPENSATION</b>	
RGND	Reference ground when using internal 1.2 V reference. Connect to AVDD to disable internal reference.
VREF	Reference input/output. Serves as an input when internal reference is disabled. Serves as a 1.2 V reference output when internal reference is enabled. Requires a 0.1 $\mu$ F capacitor tied to AGND when internal reference is enabled.
RSET	Full-scale current output adjustment.
COMP	Internal bias node for switch driver circuitry. Use 0.1 $\mu$ F capacitor tied to AGND.
<b>POWER</b>	
AGND	Analog Supply Return.
DGND	Digital Supply Return.
AVDD	Analog +4.5 to +5.5 V supply.
DVDD	Digital +2.7 to +5.5 V supply.
N/C	No connect.

## ORDERING INFORMATION

PART NUMBER	TEMPERATURE RANGE	PACKAGE
SPT5320SIS	–40 °C to +85 °C	28L SOIC
SPT5320SIR	–40 °C to +85 °C	28L SSOP Equivalent

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